

BEI YU

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RESEARCH INTERESTS

Machine learning & combinatorial algorithms in VLSI computer aided design (CAD) and computer vision (CV).

EDUCATION

University of Texas at Austin, TX, USA Ph.D., Department of Electrical and Computer Engineering	Aug. 2010 – Aug. 2014
Tsinghua University, Beijing, P.R. China M.S., Department of Computer Science and Technology	Sep. 2007 – Jul. 2010
UESTC, Chengdu, P.R. China B.S., Information and Compute Science	Sep. 2003 – Jul. 2007

EXPERIENCE

The Chinese University of Hong Kong, NT, Hong Kong Assistant Professor, CSE Department	Aug. 2015 – present
University of Texas at Austin, TX, USA Postdoctoral Researcher	Aug. 2014 – July 2015
Oracle Inc., TX, USA Summer Intern	May 2013 – Aug. 2013
Mentor Graphics, CA, USA Summer Intern	May 2011 – Aug. 2011

SELECTED AWARDS AND HONORS

Best Paper Award	ASPDAC	2021
Best Paper Award	Integration, VLSI Journal	2018
Best Paper Award	ISPD	2017
Best Paper Award	ICCAD	2013
Best Paper Award	ASPDAC	2012
Best Student Paper Award	ICTAI	2019
Best Student Paper Award	SPIE	2016
Best Paper Award Nomination	DATE	2021
Best Paper Award Nomination	ASPDAC	2019
Best Paper Award Nomination	DAC	2014
Best Paper Award Nomination	ASPDAC	2013
Best Paper Award Nomination	ICCAD	2011
Outstanding Dissertation Award	EDAA	2014
Outstanding Students Abroad Award	China Scholarship Council	2014
SPIE Scholarship	SPIE	2013
IBM Ph.D. Scholarship	IBM	2012
1st Place Award in CAD Contest	ICCAD	2015
2nd Place Award in CAD Contest	ICCAD	2018
2nd Place Award in CAD Contest	ICCAD	2013
2nd Place Award in CAD Contest	ICCAD	2012
3rd Place Award in ISPD Contest	ISPD	2020
3rd Place Award in ISPD Contest	ISPD	2017

PUBLICATIONS

Journal Papers

- [J61] Wei Zhong, Shuxiang Hu, Yuzhe Ma, Haoyu Yang, Xiuyuan Ma, Bei Yu, “[Deep Learning-Driven Simultaneous Layout Decomposition and Mask Optimization](#)”, accepted by IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**).
- [J60] Guyue Huang, Jingbo Hu, Yifan He, Jialong Liu, Mingyuan Ma, Zhaoyang Shen, Juejian Wu, Yuanfan Xu, Hengrui Zhang, Kai Zhong, Xuefei Ning, Yuzhe Ma, Haoyu Yang, Bei Yu, Huazhong Yang, Yu Wang, “Machine Learning for Electronic Design Automation: A Survey”, accepted by ACM Transactions on Design Automation of Electronic Systems (**TODAES**).

- [J59] Haocheng Li, Wing-Kai Chow, Gengjie Chen, Bei Yu, and Evangeline F.Y. Young, “[Pin-Accessible Legalization for Mixed-Cell-Height Circuits](#)”, accepted by IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**).
- [J58] Wei Li, Yuzhe Ma, Qi Sun, Lu Zhang, Yibo Lin, Iris Hui-Ru Jiang, Bei Yu, David Z. Pan, “[OpenMPL: An Open Source Layout Decomposer](#)”, accepted by IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**).
- [J57] Haocheng Li, Satwik Patnaik, Mohammed Ashraf, Haoyu Yang, Johann Knechtel, Bei Yu, Ozgur Sinanoglu, Evangeline F.Y. Young, “[Deep Learning Analysis for Split Manufactured Layouts with Routing Perturbation](#)”, accepted by IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**).
- [J56] Ran Chen, Wei Zhong, Haoyu Yang, Hao Geng, Fan Yang, Xuan Zeng, Bei Yu, “[Faster Region-based Hotspot Detection](#)”, accepted by IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**).
- [J55] Yiyang Jiang, Fan Yang, Bei Yu, Dian Zhou, Xuan Zeng, “[Efficient Layout Hotspot Detection via Binarized Residual Neural Network Ensemble](#)”, accepted by IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**).
- [J54] Haoyu Yang, Shuhe Li, Cyrus Tabery, Bingqing Lin, Bei Yu, “[Bridging the Gap Between Layout Pattern Sampling and Hotspot Detection via Batch Active Learning](#)”, accepted by IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**).
- [J53] Tinghuan Chen, Bingqing Lin, Hao Geng, Shiyan Hu, Bei Yu, “[Leveraging Spatial Correlation for Sensor Drift Calibration in Smart Building](#)”, accepted by IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**).
- [J52] Haoyu Yang, Wei Zhong, Yuzhe Ma, Hao Geng, Ran Chen, Wanli Chen, Bei Yu, “[VLSI Mask Optimization: From Shallow To Deep Learning](#)”, Integration, the VLSI Journal, vol. 77, Mar., pp. 96–103, 2021.
- [J51] Xiaowei Xu, Xinyi Zhang, Bei Yu, Xiaobo Sharon Hu, Christopher Rowen, Jingtong Hu, Yiyu Shi, “[DAC-SDC Low Power Object Detection Challenge for UAV Applications](#)”, IEEE Transactions on Pattern Analysis and Machine Intelligence (**TPAMI**), vol. 43, no. 2, pp. 392–403, 2021.
- [J50] Yuzhe Ma, Wei Zhong, Shuxiang Hu, Jih-Rong Gao, Jian Kuang, Jin Miao, Bei Yu, “[A Unified Framework for Simultaneous Layout Decomposition and Mask Optimization](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 39, no. 12, pp. 5069–5082, 2020.
- [J49] Grace Li Zhang, Bing Li, Meng Li, Bei Yu, David Z. Pan, Michaela Brunner, Georg Sigl, Ulf Schlichtmann, “[TimingCamouflage+: Netlist Security Enhancement with Unconventional Timing](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 39, no. 12, pp. 4482–4495, 2020.
- [J48] Hao Geng, Wei Zhong, Haoyu Yang, Yuzhe Ma, Joydeep Mitra, Bei Yu, “[SRAF Insertion via Supervised Dictionary Learning](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 39, no. 10, pp. 2849–2859, 2020.
- [J47] Haoyu Yang, Shuhe Li, Zihao Deng, Yuzhe Ma, Bei Yu, and Evangeline F. Y. Young, “[GAN-OPC: Mask Optimization with Lithography-guided Generative Adversarial Nets](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 39, no. 10, pp. 2822–2834, 2020.
- [J46] Kang Liu, Haoyu Yang, Yuzhe Ma, Benjamin Tan, Bei Yu, Evangeline F. Y. Young, Ramesh Karri, Siddharth Garg, “[Are Adversarial Perturbations a Showstopper for ML-Based CAD? A Case Study on CNN-Based Lithographic Hotspot Detection](#)”, ACM Transactions on Design Automation of Electronic Systems (**TODAES**), vol. 25, no. 5, 2020.
- [J45] Qi Xu, Song Chen, Hao GENG, Bo Yuan, Bei Yu, Feng Wu, Zhengfeng Huang, “[Fault Tolerance in Memristive Crossbar-Based Neuromorphic Computing Systems](#)”, Integration, the VLSI Journal, vol. 70, Jan., pp. 70–79, 2020.
- [J44] Xingquan Li, Bei Yu, Jianli Chen, Wenxing Zhu, “[DSA Guiding Template Assignment with Multiple Redundant Via and Dummy Via Insertion](#)”, Integration, the VLSI Journal, vol. 70, Jan., pp. 32–42, 2020.
- [J43] Yuzhe Ma, Subhendu Roy, Jin Miao, Jiamin Chen, Bei Yu, “[Cross-layer Optimization for High Speed Adders: A Pareto Driven Machine Learning Approach](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 38, no. 12, pp. 2298–2311, 2019.
- [J42] Qi Xu, Hao Geng, Song Chen, Bei Yu, Feng Wu, “[Memristive Crossbar Mapping for Neuromorphic Computing Systems on 3D IC](#)”, ACM Transactions on Design Automation of Electronic Systems (**TODAES**), vol. 25, no. 1, pp. 8:1–8:19, 2019.
- [J41] Meng Li, Bei Yu, Yibo Lin, Xiaoqing Xu, Wuxi Li, David Z. Pan, “[A Practical Split Manufacturing Framework for Trojan Prevention via Simultaneous Wire Lifting and Cell Insertion](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 38, no. 9, pp. 1585–1598, 2019.
- [J40] Meng Li, Kaveh Shamsi, Travis Meade, Zheng Zhao, Bei Yu, Yier Jin, David Z. Pan, “[Provably Secure Camouflaging Strategy for IC Protection](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 38, no. 8, pp. 1399–1412, 2019.

- [J39] Haoyu Yang, Jing Su, Yi Zou, Yuzhe Ma, Bei Yu, Evangeline F. Y. Young, “[Layout Hotspot Detection with Feature Tensor Generation and Deep Biased Learning](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 38, no. 6, pp. 1175–1187, 2019.
- [J38] Derong Liu, Bei Yu, Vinicius Livramento, Salim Chowdhury, Duo Ding, Huy Vo, Akshay Sharma, David Z. Pan, “[Synergistic Topology Generation and Route Synthesis for On-Chip Performance-Critical Signal Groups](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 38, no. 6, pp. 1147–1160, 2019.
- [J37] Song Chen, Qi Xu, Bei Yu, “[Adaptive 3D-IC TSV Fault Tolerance Structure Generation](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 38, no. 5, pp. 949–960, 2019.
- [J36] Qianru Zhang, Meng Zhang, Tinghuan Chen, Zhifei Sun, Yuzhe Ma, Bei Yu, “[Recent Advances in Convolutional Neural Network Acceleration](#)”, Neurocomputing, vol. 323, pp. 37–51, Jan., 2019.
- [J35] Xingquan Li, Bei Yu, Jiaojiao Ou, Jianli Chen, David Z. Pan, Wenxing Zhu, “[Graph Based Redundant Via Insertion and Guiding Template Assignment for DSA-MP](#)”, IEEE Transactions on Very Large Scale Integration Systems (**TVLSI**), vol. 26, no. 11, pp. 2504–2517, 2018.
- [J34] Jian Kuang, Evangeline F. Y. Young, Bei Yu, “[CRMA: Incorporating Cut Redistribution with Mask Assignment to Enable the Fabrication of 1D Gridded Design](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 37, no. 10, pp. 2036–2049, 2018.
- [J33] Gengjie Chen, Chak-Wa Pui, Wing-Kai Chow, Ka-Chun Lam, Jian Kuang, Evangeline F. Y. Young, Bei Yu, “[RippleFPGA: Routability-Driven Simultaneous Packing and Placement for Modern FPGAs](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 37, no. 10, pp. 2022–2035, 2018.
- [J32] Yibo Lin, Bei Yu, Meng Li, David Z. Pan, “[Layout Synthesis for Topological Quantum Circuits with 1D and 2D Architectures](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 37, no. 8, pp. 1574–1587, 2018.
- [J31] Shiyao Hu, Bei Yu, Huafeng Yu, “[Guest Editorial on Special Issue on Sustainable Cyber-Physical Systems](#)”, IEEE Transactions on Sustainable Computing (TSUSC), vol. 3, no. 2, pp. 58–59, 2018.
- [J30] Yibo Lin, Bei Yu, Xiaoqing Xu, Jih-Rong Gao, Natarajan Viswanathan, Wen-Hao Liu, Zhuo Li, Charles J. Alpert, David Z. Pan, “[MrDP: Multiple-row Detailed Placement of Heterogeneous-sized Cells for Advanced Nodes](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 37, no. 6, pp. 1237–1250, 2018.
- [J29] Jin Miao, Meng Li, Subhendu Roy, Yuzhe Ma, Bei Yu, “[SD-PUF: Spliced Digital Physical Unclonable Function](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 37, no. 5, pp. 927–940, 2018.
- [J28] Derong Liu, Bei Yu, Salim Chowdhury, David Z. Pan, “[TILA-S: Timing-Driven Incremental Layer Assignment Avoiding Slew Violations](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 37, no. 1, pp. 231–244, 2018.
- [J27] Xiaotao Jia, Yici Cai, Qiang Zhou, Bei Yu, “[A Multi-Commodity Flow based Detailed Router with Efficient Acceleration Techniques](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 37, no. 1, pp. 217–230, 2018.
- [J26] Haoyu Yang, Luyang Luo, Jing Su, Chenxi Lin, Bei Yu, “[Imbalance Aware Lithography Hotspot Detection: A Deep Learning Approach](#)”, Journal of Micro/Nanolithography, MEMS, and MOEMS (JM3), vol. 16, no. 3, 033504, 2017.
- [J25] Yibo Lin, Xiaoqing Xu, Bei Yu, Ross Baldick, David Z. Pan, “[Triple/Quadruple Patterning Layout Decomposition via Novel Linear Programming and Iterative Rounding](#)”, Journal of Micro/Nanolithography, MEMS, and MOEMS (JM3), vol. 16, no. 2, 023507, 2017.
- [J24] Derong Liu, Bei Yu, Salim Chowdhury, David Z. Pan, “[Incremental Layer Assignment for Timing Optimization](#)”, ACM Transactions on Design Automation of Electronic Systems (**TODAES**), vol. 22, no. 75, pp. 75:1–75:25, 2017.
- [J23] Yibo Lin, Bei Yu, David Z. Pan, “[High Performance Dummy Fill Insertion with Coupling and Uniformity Constraints](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 36, no. 9, pp. 1532–1544, 2017.
- [J22] Qi Xu, Song Chen, Xiaodong Xu, Bei Yu, “[Clustered Fault Tolerance TSV Planning for 3D Integrated Circuits](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 36, no. 8, pp. 1287–1300, 2017.
- [J21] Yibo Lin, Bei Yu, Biying Xu, David Z. Pan, “[Triple Patterning Aware Detailed Placement Toward Zero Cross-Row Middle-of-Line Conflict](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 36, no. 7, pp. 1140–1152, 2017.
- [J20] Vinicius Livramento, Derong Liu, Salim Chowdhury, Bei Yu, Xiaoqing Xu, David Z. Pan, José Luís Güntzel, Luiz C. V. dos Santos, “[Incremental Layer Assignment Driven by an External Signoff Timing Engine](#)”, IEEE

Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 36, no. 7, pp. 1126–1139, 2017.

- [J19] Yibo Lin, Bei Yu, Yi Zou, Zhuo Li, Charles J. Alpert, David Z. Pan, “[Stitch Aware Detailed Placement for Multiple E-Beam Lithography](#)”, Integration, the VLSI Journal, vol. 58, June, pp. 47–54, 2017. (**Best Paper Award**)
- [J18] Meikang Qiu, Saurabh Garg, Rujkumar Buyya, Bei Yu, Shiyan Hu, “[Special Issue on Scalable Cyber-Physical Systems](#)”, Journal of Parallel and Distributed Computing (JPDC), vol. 103, pp. 1–2, May 2017.
- [J17] Bingqing Lin, Bei Yu, “[Smart Building Uncertainty Analysis via Adaptive Lasso](#)”, IET Cyber-Physical Systems: Theory & Applications (IET-CPS), vol. 2, no. 1, pp. 1–7, 2017.
- [J16] Tetsuaki Matsunawa, Bei Yu, David Z. Pan, “[Laplacian Eigenmaps and Bayesian Clustering Based Layout Pattern Sampling and Its Applications to Hotspot Detection and OPC](#)”, Journal of Micro/Nanolithography, MEMS, and MOEMS (JM3), vol. 15, no. 4, 043504, 2016.
- [J15] Bei Yu, Xiaoqing Xu, Subhendu Roy, Yibo Lin, Jiaojiao Ou, David Z. Pan, “[Design for Manufacturability and Reliability in Extreme-Scaling VLSI](#)”, Science China Information Sciences (SCIS), vol. 59, June, 061406:2, 2016.
- [J14] Bei Yu, Kun Yuan, Jih-Rong Gao, Shiyan Hu, David Z. Pan, “[EBL Overlapping Aware Stencil Planning for MCC System](#)”, ACM Transactions on Design Automation of Electronic Systems (**TODAES**), vol. 21, no. 3, pp. 43:1–43:24, 2016.
- [J13] Xiaoqing Xu, Bei Yu, Jih-Rong Gao, Che-Lun Hsu, David Z. Pan, “[PARR: Pin Access Planning and Regular Routing for Self-Aligned Double Patterning](#)”, ACM Transactions on Design Automation of Electronic Systems (**TODAES**), vol. 21, no. 3, pp. 42:1–42:21, 2016.
- [J12] Tetsuaki Matsunawa, Bei Yu, David Z. Pan, “[Optical Proximity Correction with Hierarchical Bayes Model](#)”, Journal of Micro/Nanolithography, MEMS, and MOEMS (JM3), vol. 15, no. 2, 021009, 2016.
- [J11] Xiaoqing Xu, Brian Cline, Greg Yeric, Bei Yu, David Z. Pan, “[Systematic Framework for Evaluating Standard Cell Middle-Of-Line \(MOL\) Robustness for Multiple Patterning Lithography](#)”, Journal of Micro/Nanolithography, MEMS, and MOEMS (JM3), vol. 15, no. 2, 021202, 2016.
- [J10] Jiaojiao Ou, Bei Yu, Jih-Rong Gao, David Z. Pan, “[Directed Self-Assembly Cut Mask Assignment for 1D Design](#)”, Journal of Micro/Nanolithography, MEMS, and MOEMS (JM3), vol. 14, no. 3, 031211, 2015.
- [J9] Xiaoqing Xu, Brian Cline, Greg Yeric, Bei Yu, David Z. Pan, “[Self-Aligned Double Patterning Aware Pin Access and Standard Cell Layout Co-Optimization](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 34, no. 5, pp. 699–712, 2015.
- [J8] Bei Yu, Xiaoqing Xu, Jih-Rong Gao, Yibo Lin, Zhuo Li, Charles Alpert, David Z. Pan, “[Methodology for Standard Cell Compliance and Detailed Placement for Triple Patterning Lithography](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 34, no. 5, pp. 726–739, 2015.
- [J7] Bei Yu, Kun Yuan, Duo Ding, David Z. Pan, “[Layout Decomposition for Triple Patterning Lithography](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 34, no. 3, pp. 433–446, 2015.
- [J6] Bei Yu, Jih-Rong Gao, Duo Ding, Xuan Zeng, David Z. Pan, “[Accurate Lithography Hotspot Detection based on PCA-SVM Classifier with Hierarchical Data Clustering](#)”, Journal of Micro/Nanolithography, MEMS, and MOEMS (JM3), vol. 14, no. 1, 011003, 2015.
- [J5] Bei Yu, Subhendu Roy, Jih-Rong Gao, David Z. Pan, “[Triple-patterning lithography \(TPL\) layout decomposition using end-cutting](#)”, Journal of Micro/Nanolithography, MEMS, and MOEMS (JM3), vol. 14, no. 1, 011002, 2015.
- [J4] David Z. Pan, Bei Yu, Jih-Rong Gao, “[Design for Manufacturing with Emerging Nanolithography](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 32, no. 10, pp. 1453–1472, 2013. (**Keynote Paper**)
- [J3] Kun Yuan, Bei Yu, David Z. Pan, “[E-Beam Lithography Stencil Planning and Optimization with Overlapped Characters](#)”, IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems (**TCAD**), vol. 31, no. 2, pp. 167–179, Feb. 2012.
- [J2] Wei Zhong, Takeshi Yoshimura, Bei Yu, Song Chen, Sheqin Dong, Satoshi Goto, “[Application-Specific Network-on-Chip Synthesis: Cluster Generation and Network Component Insertion](#)”, IEICE Transactions on Fundamentals of Electronics, Communications and Computer Sciences, vol. E95-C, no. 4, pp. 535–545, 2012.
- [J1] Bei Yu, Sheqin Dong, Song Chen, Satoshi Goto, “[Voltage and Level-Shifter Assignment Driven Floorplanning](#)”, IEICE Transactions on Fundamentals of Electronics, Communications and Computer Sciences, vol. E92-A, no. 12, Dec. 2009.

Conference Papers

- [C119] Junzhe Cai, Changhao Yan, Yuzhe Ma, Bei Yu, Dian Zhou, Xuan Zeng, “[NeurFill: Migrating Full-Chip CMP Simulators to Neural Networks for Model-Based Dummy Filling Synthesis](#)”, ACM/IEEE Design Automation Conference (**DAC**), San Francisco, CA, July 11–15, 2021.

- [C118] Yifeng Xiao, Miaodi Su, Haoyu Yang, Jianli Chen, Jun Yu, Bei Yu, “Low-Cost Lithography Hotspot Detection with Active Entropy Sampling and Model Calibration”, ACM/IEEE Design Automation Conference (**DAC**), San Francisco, CA, July 11–15, 2021.
- [C117] Haoyu Yang, Shuhe Li, Bei Yu, “[Routing Towards Discriminative Power of Class Capsules](#)”, arXiv preprint:2103.04278.
- [C116] Wei Li, Guojin Chen, Haoyu Yang, Ran Chen, Bei Yu, “Learning Point Clouds in EDA”, ACM International Symposium on Physical Design (ISPD), Mar. 21–24, 2021. (**Invited Paper**)
- [C115] Ziyang Yu, Guojin Chen, Yuzhe Ma, Bei Yu, “A GPU-enabled Level-Set Method for Mask Optimization”, IEEE/ACM Proceedings Design, Automation and Test in Europe (**DATE**), Feb. 01–05, 2021.
- [C114] Qi Sun, Tinghuan Chen, Siting Liu, Jin Miao, Jianli Chen, Hao Yu, Bei Yu, “Correlated Multi-objective Multi-fidelity Optimization for HLS Directives Design”, IEEE/ACM Proceedings Design, Automation and Test in Europe (**DATE**), Feb. 01–05, 2021. (**Best Paper Award Nomination**)
- [C113] Qi Sun, Chen Bai, Hao Geng, Bei Yu, “Deep Neural Network Hardware Deployment Optimization via Advanced Active Learning”, IEEE/ACM Proceedings Design, Automation and Test in Europe (**DATE**), Feb. 01–05, 2021.
- [C112] Siting Liu, Qi Sun, Peiyu Liao, Yibo Lin, Bei Yu, “Global Placement with Deep Learning-Enabled Explicit Routability Optimization”, IEEE/ACM Proceedings Design, Automation and Test in Europe (**DATE**), Feb. 01–05, 2021.
- [C111] Hongjia Li, Mengshu Sun, Tianyun Zhang, Olivia Chen, Nobuyuki Yoshikawa, Bei Yu, Yanzhi Wang, Yibo Lin, “AQFP-Capable Physical Design Automation”, IEEE/ACM Proceedings Design, Automation and Test in Europe (**DATE**), Feb. 01–05, 2021.
- [C110] Zhuolun He, Peiyu Liao, Siting Liu, Yuzhe Ma, Bei Yu, “[Physical Synthesis for Advanced Neural Network Processors](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), Jan. 18–21, 2021. (**Invited Paper**)
- [C109] Wei Li, Yuxiao Qu, Gengjie Chen, Yuzhe Ma, Bei Yu, “[TreeNet: Deep Point Cloud Embedding for Routing Tree Construction](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), Jan. 18–21, 2021. (**Best Paper Award**)
- [C108] Tinghuan Chen, Qi Sun, Canhui Zhan, Changze Liu, Huatao Yu, Bei Yu, “[Analog IC Aging-induced Degradation Estimation via Heterogeneous Graph Convolutional Networks](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), Jan. 18–21, 2021.
- [C107] Haoyu Yang, Shifan Zhang, Kang Liu, Siting Liu, Benjamin Tan, Ramesh Karri, Siddharth Garg, Bei Yu, Evangeline F.Y. Young, “[Attacking a CNN-based Layout Hotspot Detector Using Group Gradient Method](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), Jan. 18–21, 2021.
- [C106] Hao Geng, Haoyu Yang, Lu Zhang, Jin Miao, Fan Yang, Xuan Zeng, Bei Yu, “[Hotspot Detection via Attention-based Deep Layout Metric Learning](#)”, IEEE/ACM International Conference on Computer-Aided Design (**ICCAD**), Nov. 2–5, 2020.
- [C105] Qi Sun, Arjun Ashok Rao, Xufeng Yao, Bei Yu, Shiyang Hu, “[Counteracting Adversarial Attack in Autonomous Driving](#)”, IEEE/ACM International Conference on Computer-Aided Design (**ICCAD**), Nov. 2–5, 2020. (**Invited Paper**)
- [C104] Guojin Chen, wanli chen, Yuzhe Ma, Haoyu Yang, Bei Yu, “[DAMO: Deep Agile Mask Optimization for Full Chip Scale](#)”, IEEE/ACM International Conference on Computer-Aided Design (**ICCAD**), Nov. 2–5, 2020.
- [C103] Bientian Jiang, Lixin Liu, Yuzhe Ma, Hang Zhang, Evangeline F. Y. Young, Bei Yu, “[Neural-ILT: Migrating ILT to Neural Networks for Mask Printability and Complexity Co-optimization](#)”, IEEE/ACM International Conference on Computer-Aided Design (**ICCAD**), Nov. 2–5, 2020.
- [C102] Zhuolun He, Lu Zhang, Peiyu Liao, Yuzhe Ma, Bei Yu, “[Reinforcement Learning Driven Physical Synthesis](#)”, IEEE International Conference on Solid-State and Integrated Circuit Technology (ICSICT), Kunming, Nov. 3–6, 2020. (**Invited Paper**)
- [C101] Zhuolun He, Yuzhe Ma, Lu Zhang, Peiyu Liao, Ngai Wong, Bei Yu, Martin D. F. Wong, “[Learn to Floorplan through Acquisition of Effective Local Search Heuristics](#)”, IEEE International Conference on Computer Design (**ICCD**), Oct. 18–21, 2020.
- [C100] Wanli Chen, Xinge Zhu, Ruoqi Sun, Junjun He, Ruiyu Li, Xiaoyong Shen, Bei Yu, “[Tensor Low-Rank Reconstruction for Semantic Segmentation](#)”, European Conference on Computer Vision (**ECCV**), August 23–28, 2020.
- [C99] Ran Chen, Yong Liu, Mengdan Zhang, Shu Liu, Bei Yu, Yu-Wing Tai, “[Dive Deeper Into Box for Object Detection](#)”, European Conference on Computer Vision (**ECCV**), August 23–28, 2020.
- [C98] Wei Li, Jialu Xia, Yuzhe Ma, Jialu Li, Yibo Lin, Bei Yu, “[Adaptive Layout Decomposition with Graph Embedding Neural Networks](#)”, ACM/IEEE Design Automation Conference (**DAC**), San Francisco, CA, July 19–23, 2020.

- [C97] Wei Zhong, Shuxiang Hu, Yuzhe Ma, Haoyu Yang, Xiuyuan Ma, Bei Yu, “[Deep Learning-Driven Simultaneous Layout Decomposition and Mask Optimization](#)”, ACM/IEEE Design Automation Conference (**DAC**), San Francisco, CA, July 19–23, 2020.
- [C96] Husheng Zhou, Wei Li, Zelun Kong, Junfeng Guo, Yuqun Zhang, Bei Yu, Lingming Zhang, Cong Liu, “[Deep-Board: Systematic Physical-World Testing of Autonomous Driving Systems](#)”, ACM/IEEE International Conference on Software Engineering (**ICSE**), Seoul, May 23–29, 2020.
- [C95] Junpeng Wang, Qi Xu, Bo Yuan, Song Chen, Bei Yu, Feng Wu, “[Reliability-Driven Neural Network Training for Memristive Crossbar-Based Neuromorphic Computing Systems](#)”, IEEE International Symposium on Circuits and Systems (ISCAS), Sevilla, Spain, May 17–20, 2020.
- [C94] Yuzhe Ma, Zhuolun He, Wei Li, Tinghuan Chen, Lu Zhang, Bei Yu, “[Understanding Graphs in EDA: From Shallow to Deep Learning](#)”, ACM International Symposium on Physical Design (ISPD), Taipei, Mar. 25–Apr. 01, 2020. (**Invited Paper**)
- [C93] Haoyu Yang, Wei Zhong, Yuzhe Ma, Hao Geng, Ran Chen, Wanli Chen, Bei Yu, “[VLSI Mask Optimization: From Shallow To Deep Learning](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASP-DAC), Beijing, Jan. 13–16, 2020. (**Invited Paper**)
- [C92] Qi Sun, Tinghuan Chen, Jin Miao, Bei Yu, “[Power-Driven DNN Dataflow Optimization on FPGA](#)”, IEEE/ACM International Conference on Computer-Aided Design (**ICCAD**), Westminster, CO, Nov. 4–7, 2019. (**Invited Paper**)
- [C91] Yuzhe Ma, Ran Chen, Wei Li, Fanhua Shang, Wenjian Yu, Minsik Cho, Bei Yu, “[A Unified Approximation Framework for Compressing and Accelerating Deep Neural Networks](#)”, IEEE International Conference on Tools with Artificial Intelligence (ICTAI), Portland, OR, Nov. 4–6, 2019. (**Best Student Paper Award**)
- [C90] Wei Li, Yuzhe Ma, Qi Sun, Yibo Lin, Iris Hui-Ru Jiang, Bei Yu, David Z. Pan, “[OpenMPL: An Open Source Layout Decomposer](#)”, IEEE International Conference on ASIC (ASICON), Chongqing, China, Oct. 29–Nov. 1, 2019. (**Invited Paper**)
- [C89] Yuzhe Ma, Ziyang Yu, Bei Yu, “[CAD Tool Design Space Exploration via Bayesian Optimization](#)”, ACM/IEEE Workshop on Machine Learning for CAD (MLCAD), Alberta, Canada, Sep. 3–4, 2019.
- [C88] Haoyu Yang, Wen Chen, Piyush Pathak, Frank Gennari, Ya-Chieh Lai, Bei Yu, “[Automatic Layout Generation with Applications in Machine Learning Engine Evaluation](#)”, ACM/IEEE Workshop on Machine Learning for CAD (MLCAD), Alberta, Canada, Sep. 3–4, 2019.
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- [C86] Haoyu Yang, Piyush Pathak, Frank Gennari, Ya-Chieh Lai, Bei Yu, “[DeePattern: Layout Pattern Generation with Transforming Convolutional Auto-Encoder](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 148:1–148:6, Las Vegas, NV, June 2–6, 2019.
- [C85] Yuzhe Ma, Haoxing Ren, Brucek Khailany, Harbinder Sikka, Lijuan Luo, Karthikeyan Natarajan, Bei Yu, “[High Performance Graph Convolutional Networks with Applications in Testability Analysis](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 18:1–18:6, Las Vegas, NV, June 2–6, 2019.
- [C84] Tinghuan Chen, Bingqing Lin, Hao Geng, Bei Yu, “[Sensor Drift Calibration via Spatial Correlation Model in Smart Building](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 105:1–105:6, Las Vegas, NV, June 2–6, 2019.
- [C83] Ran Chen, Wei Zhong, Haoyu Yang, Hao Geng, Xuan Zeng, Bei Yu, “[Faster Region-based Hotspot Detection](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 146:1–146:6, Las Vegas, NV, June 2–6, 2019.
- [C82] Yiyang Jiang, Fan Yang, Hengliang Zhu, Bei Yu, Dian Zhou, Xuan Zeng, “[Efficient Layout Hotspot Detection via Binarized Residual Neural Network](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 147:1–147:6, Las Vegas, NV, June 2–6, 2019.
- [C81] Haocheng Li, Satwik Patnaik, Abhrajit Sengupta, Haoyu Yang, Johann Knechtel, Bei Yu, Evangeline F. Y. Young, Ozgur Sinanoglu, “[Attacking Split Manufacturing from a Deep Learning Perspective](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 135:1–135:6, Las Vegas, NV, June 2–6, 2019.
- [C80] Bentian Jiang, Xiaopeng Zhang, Ran Chen, Gengjie Chen, Peishan Tu, Wei Li, Evangeline F. Y. Young, Bei Yu, “[FIT: Fill Insertion Considering Timing](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 221:1–221:6, Las Vegas, NV, June 2–6, 2019.
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- [C77] Xingquan Li, Bei Yu, Jianli Chen, Wenxing Zhu, “[A Local Optimal Method on DSA Guiding Template Assignment with Redundant Dummy Via Insertion](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), pp. 305–310, Tokyo, Jan. 21–24, 2019. (**Invited Paper**)
- [C76] Hao Geng, Haoyu Yang, Yuzhe Ma, Joydeep Mitra, Bei Yu, “[SRAF Insertion via Supervised Dictionary Learning](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), pp. 406–411, Tokyo, Jan. 21–24, 2019. (**Best Paper Award Nomination**)
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- [C73] Haoyu Yang, Shuhe Li, Yuzhe Ma, Bei Yu, Evangeline F. Y. Young, “[GAN-OPC: Mask Optimization with Lithography-guided Generative Adversarial Nets](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 136:1–136:6, San Francisco, CA, June 24–28, 2018.
- [C72] Haocheng Li, Wing-Kai Chow, Gengjie Chen, Evangeline F. Y. Young, Bei Yu, “[Routability-Driven and Fence-Aware Legalization for Mixed-Cell-Height Circuits](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 150:1–150:6, San Francisco, CA, June 24–28, 2018.
- [C71] Fengxian Jiao, Sheqin Dong, Bei Yu, Bing Li, Ulf Schlichtmann, “[Thermal-Aware Placement and Routing for 3D Optical Networks-on-Chips](#)”, IEEE International Symposium on Circuits and Systems (ISCAS), pp. 1–4, Florence, May 27–30, 2018.
- [C70] Qi Xu, Song Chen, Bei Yu, Feng Wu, “[Memristive Crossbar Mapping for Neuromorphic Computing Systems on 3D IC](#)”, ACM Great Lakes Symposium on VLSI (GLSVLSI), pp. 451–454, Chicago, IL, May 23–25, 2018.
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- [C65] Yuzhe Ma, Jih-Rong Gao, Jian Kuang, Jin Miao, Bei Yu, “[A Unified Framework for Simultaneous Layout Decomposition and Mask Optimization](#)”, IEEE/ACM International Conference on Computer-Aided Design (**ICCAD**), pp. 81–88, Irvine, CA, Nov. 13–16, 2017.
- [C64] Yuzhe Ma, Xuan Zeng, Bei Yu, “[Methodologies for Layout Decomposition and Mask Optimization: A Systematic Review](#)”, IFIP/IEEE International Conference on Very Large Scale Integration (VLSI-SoC), Abu Dhabi, UAE, Oct. 23–25, 2017. (**Invited Paper**)
- [C63] Cheng Zhuo, Bei Yu, Di Gao, “[Accelerating Chip Design with Machine Learning: From Pre-Silicon to Post-Silicon](#)”, IEEE International System-on-Chip Conference (SOCC), pp. 227–232, Munich, Germany, September 5–8, 2017. (**Invited Paper**)
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- [C56] Jiaojiao Ou, Bei Yu, Xiaoqing Xu, Joydeep Mitra, Yibo Lin, David Z. Pan, “[DSAR: DSA aware Routing with Simultaneous DSA Guiding Pattern and Double Patterning Assignment](#)”, ACM International Symposium on Physical Design (ISPD), pp. 91–98, Portland, OR, Mar. 19–22, 2017.
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- [C54] Chak-Wa Pui, Gengjie Chen, Wing-Kai Chow, Jian Kuang, Ka-Chun Lam, Peishan Tu, Hang Zhang, Evangeline F. Y. Young, Bei Yu, “[RippleFPGA: A Routability-Driven Placement for Large-Scale Heterogeneous FPGAs](#)”, IEEE/ACM International Conference on Computer-Aided Design (ICCAD), pp. 67:1–67:8, Austin, TX, Nov. 7–10, 2016. (**Invited Paper**)
- [C53] Jian Kuang, Evangeline F. Y. Young, Bei Yu, “[Incorporating Cut Redistribution with Mask Assignment to Enable 1D Gridded Design](#)”, IEEE/ACM International Conference on Computer-Aided Design (ICCAD), pp. 48:1–48:8, Austin, TX, Nov. 7–10, 2016.
- [C52] Hang Zhang, Bei Yu, Evangeline F. Y. Young, “[Enabling Online Learning in Lithography Hotspot Detection with Information-Theoretic Feature Optimization](#)”, IEEE/ACM International Conference on Computer-Aided Design (ICCAD), pp. 47:1–47:8, Austin, TX, Nov. 7–10, 2016.
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- [C44] Jiaojiao Ou, Bei Yu, David Z. Pan, “[Concurrent Guiding Template Assignment and Redundant Via Insertion for DSA-MP Hybrid Lithography](#)”, ACM International Symposium on Physical Design (ISPD), pp. 39–46, Sonoma, CA, April 3–6, 2016.
- [C43] Yibo Lin, Xiaoqing Xu, Bei Yu, Ross Baldick, David Z. Pan, “[Triple/Quadruple Patterning Layout Decomposition via Novel Linear Programming and Iterative Rounding](#)”, SPIE Intl. Symp. Advanced Lithography Conference, San Jose, CA, Feb. 21–25, 2016. (**Best Student Paper Award**)
- [C42] Tetsuaki Matsunawa, Bei Yu, David Z. Pan, “[Laplacian Eigenmaps and Bayesian Clustering Based Layout Pattern Sampling and Its Applications to Hotspot Detection and OPC](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), pp. 679–684, Macau, Jan. 25–28, 2016.
- [C41] Yibo Lin, Bei Yu, Yi Zou, Zhuo Li, Charles J. Alpert, David Z. Pan, “[Stitch Aware Detailed Placement for Multiple E-Beam Lithography](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), pp. 186–191, Macau, Jan. 25–28, 2016.
- [C40] Bei Yu, Derong Liu, Salim Chowdhury, David Z. Pan, “[TILA: Timing-Driven Incremental Layer Assignment](#)”, IEEE/ACM International Conference on Computer-Aided Design (ICCAD), pp. 110–117, Austin, TX, Nov. 2–6, 2015.
- [C39] Yibo Lin, Bei Yu, Biying Xu, David Z. Pan, “[Triple Patterning Aware Detailed Placement Toward Zero Cross-Row Middle-of-Line Conflict](#)”, IEEE/ACM International Conference on Computer-Aided Design (ICCAD), pp. 396–403, Austin, TX, Nov. 2–6, 2015.

- [C38] David Z. Pan, Lars Liebmann, Bei Yu, Xiaoqing Xu, Yibo Lin, “[Pushing Multiple Patterning in Sub-10nm: Are We Ready?](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 197:1–197:6, San Francisco, CA, June 7–11, 2015. (**Invited Paper**)
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- [C36] Yibo Lin, Bei Yu, David Z. Pan, “[High Performance Dummy Fill Insertion with Coupling and Uniformity Constraints](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 71:1–71:6, San Francisco, CA, June 7–11, 2015.
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- [C34] Jiaojiao Ou, Bei Yu, Jih-Rong Gao, Moshe Preil, Azat Latypov, David Z. Pan, “[Directed Self-Assembly Based Cut Mask Optimization for Unidirectional Design](#)”, ACM Great Lakes Symposium on VLSI (GLSVLSI), pp. 83–86, Pittsburgh, PA, May 20–22, 2015.
- [C33] Tetsuaki Matsunawa, Bei Yu, David Z. Pan, “[Optical proximity correction with hierarchical Bayes model](#)”, SPIE Intl. Symp. Advanced Lithography - Optical Microlithography XXVIII, San Jose, CA, Feb. 22–26, 2015.
- [C32] Tetsuaki Matsunawa, Jih-Rong Gao, Bei Yu, David Z. Pan, “[A new lithography hotspot detection framework based on AdaBoost classifier and simplified feature extraction](#)”, SPIE Intl. Symp. Advanced Lithography - Design-Process-Technology Co-optimization for Manufacturability IX, San Jose, CA, Feb. 22–26, 2015.
- [C31] Xiaoqing Xu, Brian Cline, Greg Yeric, Bei Yu, David Z. Pan, “[A systematic framework for evaluating standard cell middle-of-line \(MOL\) robustness for multiple patterning](#)”, SPIE Intl. Symp. Advanced Lithography - Design-Process-Technology Co-optimization for Manufacturability IX, San Jose, CA, Feb. 22–26, 2015.
- [C30] Bei Yu, David Z. Pan, Tetsuaki Matsunawa, Xuan Zeng, “[Machine Learning and Pattern Matching in Physical Design](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), pp. 286–293, Japan, Jan. 19–22, 2015. (**Invited Paper**)
- [C29] Jiwoo Pak, Bei Yu, David Z. Pan, “[Electromigration-aware Redundant Via Insertion](#)”, IEEE/ACM Asian and South Pacific Design Automation Conference (ASPDAC), pp. 544–549, Japan, Jan. 19–22, 2015.
- [C28] Bei Yu, Gilda Garretton, David Z. Pan, “[Layout Compliance for Triple Patterning Lithography: An Iterative Approach](#)”, SPIE/BACUS Photomask Symposium, Monterey, CA, Sept. 16–18, 2014. (**Invited Paper**)
- [C27] Bei Yu, David Z. Pan, “[Layout Decomposition for Quadruple Patterning Lithography and Beyond](#)”, SRC Techcon Conference, Austin, TX, Sept. 7–9, 2014.
- [C26] Jih-Rong Gao, Xiaoqing Xu, Bei Yu, David Z. Pan, “[MOSAIC: Mask Optimizing Solution With Process Window Aware Inverse Correction](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 52:1–52:6, San Francisco, CA, June 1–5, 2014. (**Best Paper Award Nomination**)
- [C25] Bei Yu, David Z. Pan, “[Layout Decomposition for Quadruple Patterning Lithography and Beyond](#)”, ACM/IEEE Design Automation Conference (**DAC**), pp. 53:1–53:6, San Francisco, CA, June 1–5, 2014.
- [C24] Xiaoqing Xu, Brian Cline, Greg Yeric, Bei Yu, David Z. Pan, “[Self-Aligned Double Patterning Aware Pin Access and Standard Cell Layout Co-Optimization](#)”, ACM International Symposium on Physical Design (ISPD), pp. 101–108, Petaluma, CA, March 30–April 2, 2014.
- [C23] Jih-Rong Gao, Bei Yu, Duo Ding, David Z. Pan, “[Accurate lithography hotspot detection based on PCA-SVM classifier with hierarchical data clustering](#)”, SPIE Intl. Symp. Advanced Lithography - Design-Process-Technology Co-optimization for Manufacturability VIII, San Jose, CA, Feb. 23–27, 2014.
- [C22] Bei Yu, Jih-Rong Gao, Xiaoqing Xu, David Z. Pan, “[Bridging the Gap from Mask to Physical Design for Multiple Patterning Lithography](#)”, SPIE Intl. Symp. Advanced Lithography - Design-Process-Technology Co-optimization for Manufacturability VIII, San Jose, CA, Feb. 23–27, 2014. (**Invited Paper**)
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- [C20] Bei Yu, Xiaoqing Xu, Jih-Rong Gao, David Z. Pan, “[Methodology for Standard Cell Compliance and Detailed Placement for Triple Patterning Lithography](#)”, IEEE/ACM International Conference on Computer-Aided Design (**ICCAD**), pp. 349–356, San Jose, CA, Nov. 18–21, 2013. (**William J. McCalla Best Paper Award**)
- [C19] Bei Yu, Yen-Hung Lin, Gerard Luk-Pat, Duo Ding, Kevin Lucas, David Z. Pan, “[A High-Performance Triple Patterning Layout Decomposer with Balanced Density](#)”, IEEE/ACM International Conference on Computer-Aided Design (**ICCAD**), pp. 163–169, San Jose, CA, Nov. 18–21, 2013.
- [C18] Jih-Rong Gao, Bei Yu, Duo Ding, David Z. Pan, “[Lithography Hotspot Detection and Mitigation in Nanometer VLSI](#)”, IEEE International Conference on ASIC (ASICON), pp. 1–4, Shenzhen, China, Oct. 28–31, 2013. (**Invited Paper**)

- [C17] Bei Yu, Kun Yuan, Jih-Rong Gao, David Z. Pan, “[E-BLOW: E-Beam Lithography Overlapping aware Stencil Planning for MCC System](#)”, ACM/IEEE Design Automation Conference (DAC), pp. 70:1–70:7, Austin, TX, June 2–6, 2013.
- [C16] Bei Yu, Jih-Rong Gao, David Z. Pan, “[Triple-patterning lithography \(TPL\) layout decomposition using end-cutting](#)”, SPIE Intl. Symp. Advanced Lithography, San Jose, CA, Feb. 24–28, 2013.
- [C15] Jih-Rong Gao, Bei Yu, Ru Huang, David Z. Pan, “[Self-aligned Double Patterning Friendly Configuration for Standard Cell Library Considering Placement](#)”, SPIE Intl. Symp. Advanced Lithography, San Jose, CA, Feb. 24–28, 2013.
- [C14] Bei Yu, Jih-Rong Gao, David Z. Pan, “[L-Shape based Layout Fracturing for E-Beam Lithography](#)”, IEEE/ACM Asia and South Pacific Design Automation Conference (ASPDAC), pp. 249–254, Japan, Jan. 22–25, 2013. (**Best Paper Award Nomination**)
- [C13] Bei Yu, Jih-Rong Gao, Duo Ding, Yongchan Ban, Jae-Seok Yang, Kun Yuan, Minsik Cho, David Z. Pan, “[Dealing with IC Manufacturability in Extreme Scaling](#)”, IEEE/ACM International Conference on Computer-Aided Design (ICCAD), pp. 240–242, San Jose, CA, Nov. 5–8, 2012. (**Embedded Tutorial paper**)
- [C12] Yen-Hung Lin, Bei Yu, David Z. Pan, Yih-Lang Li, “[TRIAD: A Triple Patterning Lithography Aware Detailed Router](#)”, IEEE/ACM International Conference on Computer-Aided Design (ICCAD), pp. 123–129, San Jose, CA, Nov. 5–8, 2012.
- [C11] David Z. Pan, Jih-Rong Gao, Bei Yu, “[VLSI CAD for Emerging Nanolithography](#)”, International Symposium on VLSI Design, Automation and Test (VLSI-DAT), pp. 1–4, 2012. (**Invited Paper**)
- [C10] Kevin Lucas, Chris Cork, Bei Yu, Gerry Luk-Pat, Ben Painter, David Z. Pan, “[Implications of triple patterning for 14 nm node design and patterning](#)”, SPIE Advanced Lithography Symposium Design for Manufacturability through Design-Process Integration VI (Conference 8327), Feb. 2012. (**Keynote Paper**)
- [C9] Duo Ding, Bei Yu, Joydeep Ghosh, David Z. Pan, “[EPIC: Efficient Prediction of IC Manufacturing Hotspots With A Unified Meta-Classification Formulatio](#)”, IEEE/ACM Asia and South Pacific Design Automation Conference (ASPDAC), pp. 263–270, Sydney, Australia, Jan. 30–Feb. 3, 2012. (**Best Paper Award**)
- [C8] Duo Ding, Bei Yu, David Z. Pan, “[GLOW: A Global Router for Low-Power Thermal-reliable Interconnect Synthesis using Photonic Wavelength Multiplexing](#)”, IEEE/ACM Asia and South Pacific Design Automation Conference (ASPDAC), pp. 621–626, Sydney, Australia, Jan. 30–Feb. 3, 2012.
- [C7] Bei Yu, Kun Yuan, Boyang Zhang, Duo Ding, David Z. Pan, “[Triple Patterning Lithography Layout Decomposition](#)”, IEEE/ACM International Conference on Computer-Aided Design (ICCAD), pp. 1–8, San Jose, CA, Nov. 2011. (**William J. McCalla Best Paper Award Nomination**)
- [C6] Bei Yu, Sheqin Dong, Yuchun Ma, Tao Lin, Yu Wang, Song Chen, Satoshi Goto, “[Network Flow-based Simultaneous Retiming and Slack Budgeting for Low Power Design](#)”, IEEE/ACM Asia and South Pacific Design Automation Conference (ASPDAC), pp. 473–478, Japan, Jan. 2011.
- [C5] Wei Zhong, Bei Yu, Song Chen, Takeshi Yoshimura, Sheqin Dong, Satoshi Goto, “[Application-Specific Network-on-Chip Synthesis: Cluster Generation and Network Component Insertion](#)”, IEEE International Symposium on Quality Electronic Design (ISQED), pp. 144–149, Santa Clara, CA, March 14–16, 2011.
- [C4] Bei Yu, Sheqin Dong, Song Chen, Satoshi Goto, “[Floorplanning and Topology Generation for Application-Specific Network-on-Chip](#)”, IEEE/ACM Asia and South Pacific Design Automation Conference (ASPDAC), pp. 535–540, Taipei, Jan. 2010.
- [C3] Tao Lin, Sheqin Dong, Song Chen, Bei Yu, Satoshi Goto, “[A Revisit to Voltage Partitioning Problem](#)”, ACM Great Lakes Symposium on VLSI (GLSVLSI), pp. 115–118, Providence, RI, May 16–18, 2010.
- [C2] Bei Yu, Sheqin Dong, Satoshi Goto, “[Multi-Voltage and Level-Shifter Assignment Driven Floorplanning](#)”, IEEE International Conference on ASIC (ASICON), pp. 1264–1267, Changsha, Oct. 20–23, 2009.
- [C1] Bei Yu, Sheqin Dong, Song Chen, Satoshi Goto, “[Voltage-Island Driven Floorplanning Considering Level-Shifter Positions](#)”, ACM Great Lakes Symposium on VLSI (GLSVLSI), pp. 51–56, Boston, MA, May 10–12, 2009.

Books / Book Chapters

- [B3] Shiyuan Hu, Bei Yu, “[Big Data Analytics for Cyber-Physical Systems](#)”, Springer, 2020.
- [B2] Bei Yu, David Z. Pan, “[Design for Manufacturability with Advanced Lithography](#)”, Springer, 2016.
- [B1] Bei Yu, David Z. Pan, “[Layout Decomposition for Triple Patterning](#)”, in Encyclopedia of Algorithms, M.-Y. Kao eds., Springer, 2015.

Dissertation

- [PHD] Bei Yu, “[Design for Manufacturing with Advanced Lithography](#)”, University of Texas at Austin, August 2014. (**EDAA Outstanding Dissertation Award**)

Newsletters

- [N4] Qi Sun, Tinghuan Chen, Jin Miao, Bei Yu, “[Power-Driven DNN Dataflow Optimization on FPGA](#)”, IEEE TCCPS Newsletter, Volume 05, Issue 01, Mar. 2020.

- [N3] Bei Yu, “Design for Manufacturability: From Ad Hoc Solution To Extreme Regular Design”, VLSI Circuits and Systems Letter, Volume 1, Issue 2, Oct. 2015.
- [N2] Bei Yu, Gilda Garretton, David Z. Pan, “Layout Compliance for Triple Patterning Lithography: An Iterative Approach”, SPIE Newsroom.
- [N1] Kevin Lucas, Chris Cork, Bei Yu, David Z. Pan, Gerry Luk-Pat, Alex Miloslavsky, Ben Painter, “Triple patterning in 10nm node metal lithography”, SPIE Newsroom.

ADVISING AND SUPERVISORSHIP

Current Students:

Hao Geng	Ph.D.	Fall 2017 – Present
Tinghuan Chen	Ph.D.	Fall 2017 – Present
Ran Chen	Ph.D.	Fall 2018 – Present
Qi Sun	Ph.D.	Fall 2018 – Present
Lu Zhang	Ph.D.	Fall 2018 – Present
Zhuolun He	Ph.D.	Fall 2019 – Present
Wanli Chen	Ph.D.	Fall 2019 – Present
Wei Li	MPhil.	Fall 2019 – Present
Peiyu Liao	Ph.D.	Fall 2020 – Present
Wenqian Zhao	Ph.D.	Fall 2020 – Present
Yang Bai	Ph.D.	Fall 2020 – Present
Chen Bai	Ph.D.	Fall 2020 – Present
Binwu Zhu	Ph.D.	Fall 2020 – Present
Siting Liu	Ph.D.	Fall 2020 – Present

Ph.D. Defense Committees Served:

2016: Jian Kuang; 2017: Yannan Liu, Wen Zong; 2018: Lingxiao Wei, Wing-Kai Chow; 2019: Gengjie Chen, Chak-Wa Pui; 2020: Ye Tian

Supervisions Completed:

Yuzhe Ma	PhD 2020	Senior Researcher@Huawei
Haoyu Yang	PhD 2020	Postdoc@CUHK

PROFESSIONAL SERVICE

University Committee Assignments

- Member, CUHK CSE Department Graduate Panel, 2016–present.
- Member, CUHK CSE Department Curriculum Committee, 2015–present.

Editorial Board

- **Editor**, Technical Committee on Cyber-Physical Systems (TC-CPS) Newsletter, 2019–present.
- Associate Editor, ACM Transactions on Design Automation of Electronic Systems (TODAES), 2020–present.
- Associate Editor, Integration, the VLSI Journal, 2016–present.
- Associate Editor, IET Cyber-Physical Systems: Theory & Applications, 2016–present.

Guest Editor

- IEEE Consumer Electronics Magazine Special Issue on ISVLSI
- IEEE Design & Test Special Issue on Machine Learning for CAD / EDA
- IEEE Transactions on Sustainable Computing (TSUSC) Special Issue on Sustainable Cyber-Physical Systems
- Integration, the VLSI Journal Special Issue on Emerging Technologies for System Level Design and Interconnects.
- Integration, the VLSI Journal Special Issue on ASP-DAC 2017.
- Journal of Parallel and Distributed Computing (JPDC) Special Issue on Scalable Cyber-Physical Systems

Organizers

- **Chair**, ACM Student Research Competition at ICCAD, 2018, 2019.
- Secretary and Web Chair, IEEE Technical Committee on Cyber-Physical Systems (TC-CPS), 2015–Present.
- Secretary, IEEE/ACM Asia and South Pacific Design Automation Conference (ASPDAC), 2016, 2017.
- Publication Chair, ACM/IEEE System Level Interconnect Prediction Workshop (SLIP), 2018.
- Publicity Chair, IEEE INFOCOM Workshop on Cross-Layer Cyber-Physical System Security (CPSS), 2016.
- Publicity Chair, IEEE International Conference on Cyber, Physical and Social Computing (CPSCoM), 2018.

- Publicity Chair, IEEE International Conference on Industrial Cyber-Physical Systems (ICPS), 2020.
- Publicity Chair, Hardware Aware Learning Workshop in MICCAI, 2019.
- Finance Chair, IEEE International Workshop on Smart Energy Cyber-Physical Systems, 2018.
- Special Session Chair, IEEE Computer Society Annual Symposium on VLSI (ISVLSI), 2018.
- Organizing Committee, IEEE CEDA Hong Kong Chapter, 2017–present.
- Organizing Committee, EDathon, 2017, 2018, 2019.
- Organizing Committee, IEEE International Workshop on Design Automation for Cyber-Physical Systems (DACPS), 2016, 2017, 2018.
- Organizing Committee, International System Design Contest at DAC, 2018, 2019.
- Website Administrator, ACM Special Interest Group on Design Automation (SIGDA), 2015–Present.
- Local Arrangement Chair, ACM e-Energy, 2017.

Selected PC Member

- ACM/IEEE Workshop on Machine Learning for CAD (MLCAD), 2019 (TPC Co-Chair), 2020.
- ACM/IEEE Design Automation Conference (DAC), 2016, 2017, 2018.
- ACM International Symposium on Physical Design (ISPD), 2017, 2018, 2019, 2020.
- ACM Great Lakes Symposium on VLSI (GLSVLSI), 2016, 2017, 2018 (CAD Track Chair).
- IEEE/ACM International Conference On Computer Aided Design (ICCAD), 2016, 2017, 2018.
- IEEE/ACM Proceedings Design, Automation and Test in Europe (DATE), 2020, 2021.
- IEEE/ACM Asia and South Pacific Design Automation Conference (ASPDAC), 2018, 2019, 2020, 2021.
- International Joint Conference on Artificial Intelligence (IJCAI), 2020.